



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Yoshikazu Majima, et al.  
Serial No.: 10/731,526  
Filed: December 8, 2003  
For: RETROREFLECTIVE  
PHOTOELECTRIC SENSOR  
Group Art Unit: 2878  
Examiner: Unknown  
Attorney Docket: OMRN P069

**CERTIFICATE OF MAILING**

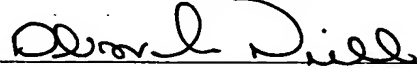
Date of Deposit: April 8, 2004

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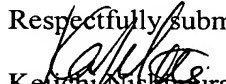
  
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**INFORMATION DISCLOSURE STATEMENT**  
**PURSUANT TO 37 C.F.R. §1.56 AND §§1.97-1.98**

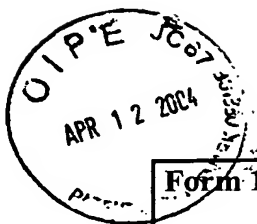
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Sir:

The following Form 1449 and a copy of a document listed thereon are being filed herewith as  
a Disclosure Statement. Consideration of this document by the Patent Examiner, and the making of it  
of record in the file of this application, are respectfully requested.

The item of information contained in this information disclosure statement was cited in a  
communication from a foreign patent office in a counterpart foreign application not more than three  
months prior to the filing of this statement.

Respectfully submitted,  
  
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April 8, 2004  
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<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Atty Docket No. OMRN P069	Application No.: 10/731,526
	Applicant: Yoshikazu Majima, et al. Filing Date December 8, 2003	Group 2878

### U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

### Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J	2001-41724	02/16/2001	JP				
	K							
	L							
	M							
	N							

### Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	O	
	P	
	Q	
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.